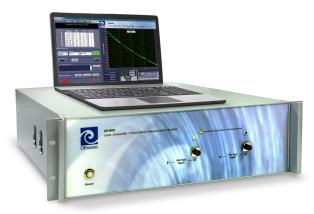


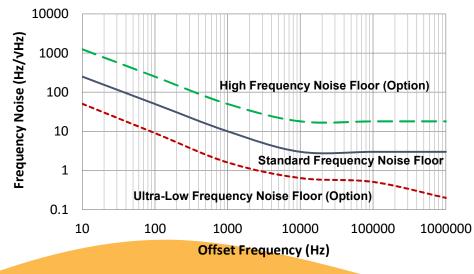
HI-Q® LASER LINEWIDTH / PHASE NOISE ANALYZER

Using a homodyne methodology, HI-Q[®] Laser Linewidth / Phase Noise Analyzer offers a fully automated measurement of ultra-low phase noise CW laser sources.



HI-Q[®] Laser Linewidth / Phase Noise Analyzer is capable of rapidly measuring laser phase noise and estimating its FWHM linewidth down to < 3 Hz without complex setup or reference lasers normally required to make such a narrow linewidth measurement.

This homodyne-based system is unique in wideband measurement without requiring another low noise reference laser source. The complete system operates with ease, speed and precision via a simple graphic user interface on a dedicated PC. No additional test equipment required. The unmatched ultra-low phase/frequency noise analyzer is scalable to various input wavelength bands and is available with low relative intensity noise (RIN) measurement option.



RIDE THE WAVE OF INNOVATION

FEATURES

- Ultra-Low Phase/Frequency Noise Measurement
- Fast Real-Time Measurement
- Instantaneous and Extended FWHM Linewidth Analysis
- No Low Noise Reference Source Required
- User Friendly Interface
- Simple PC-based Operation
- 3U x 19" Rack System
- Customizable Configurations, Upgrades, and Options

OPTIONAL CONFIGURATION

- Multiple Input Wavelength Bands within 620 nm – 2200 nm
- Ultra-Low Noise Floor
- RIN Measurements
- Extended Offset Frequency
 Range up to 500 MHz
- Extended Input Power Range
- Remote Operation
- Performance Level and Frequency
- Range Options and Upgrades

www.oewaves.com

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HI-Q® LASER LINEWIDTH, PHASE NOISE, RIN ANALYZER

| Manage | M

OE4000

SPECIFICATIONS

1530 - 1565 nm

15°C to 35°C 110 / 120 or 220 / 240 V_{ac}; 50 / 60Hz

3U x 19: Rack Mount

Frequency Noise Offset	10 Hz	100 Hz	1 kHz	1MHz	
 Ultra Low Noise Floor* 	50 Hz/√Hz	10 Hz/√Hz	2 Hz/√Hz	0.2 Hz/√Hz	
 Standard Noise Floor Option** 	250 Hz/√Hz	50 Hz/√Hz	10 Hz/√Hz	3 Hz/√Hz	
 High Noise Floor Option** 	1250 Hz/√Hz	250 Hz/√Hz	50 Hz/√Hz	18 Hz/√Hz	
* To measure laser under test (LUT) near the frequency noise floor requires LUT RIN < -100 dBc/Hz @ 10Hz, -130 dBc/Hz @ 1 kHz and -150 dBc/Hz @ 1 MHz ** To measure laser under test (LUT) near the frequency noise floor requires LUT RIN < -100 dBc/Hz @ 10Hz, -130 dBc/Hz @ 1 kHz and -140 dBc/Hz @ 1 MHz					
Lorentzian Linewidth Sensitivity (< 10 μs)		Low Noise Floor: dard Noise Floor: Noise Floor:	< 0.5 Hz < 30 Hz < 1 kHz		
FWHM Linewidth Estimated Range (< 10 ms)		Low Noise Floor: dard Noise Floor: Noise Floor:	3 Hz – 30 1 kHz – 1 10 kHz - 3		
Dynamic Range		60 dB			
White Phase Noise Floor		-160 ± 2 dBc/Hz			
Optical Input Power Range		+5 to +15 dBm (PM-FC/APC)			
Offset Frequency Range		10 Hz – 1 MHz			
Measurement Types		Frequency/Phase Noise, RIN (Option)			
Data Storage and I/O		HDD / USB Port			
Resolution Bandwidth		0.1 Hz – 200 kHz			

OPTIONS

Power

Size

Operating Temperature Range

Low or High Input Power Range ¹	Up to 15 dB within -10 to +20 dBm
Wavelength Ranges Available ²	575 - 710 / 740 - 935 / 965 - 1065 / 1000 - 1100 / 1260 - 1360 1360 - 1460 / 1460 - 1530 / 1530 - 1565 / 1565 - 1625 / 1647 - 1655 1900 - 1950 / 1950 - 2100 (Consult factory for custom or multi-wavelength range options)
Extended Offset Frequency Range	Frequency / Phase Noise Down to 1 Hz or up to 100 MHz (Consult factory for higher Offset Frequency options)
Relative Intensity Noise (RIN) Floor	-158 ± 2 dB/Hz > 1 MHz (SM-FC/APC; Offset frequency matches system specification; see OE4001 Datasheet for higher frequencies)

Note: These specifications are subject to change without notice due to OEwaves ongoing development cycle. Patents Pending.

Note: Unless otherwise noted, all system noise floors are optimum at maximum specified input power range.

¹Phase Noise and RIN noise floors are higher with Low Power option. Consult OEwaves Sales for custom low power option performance. Consult OEwaves Sales for special cases of input power < -10 dBm.

²Phase Noise and RIN Noise Floors for systems with E, S and L telecom bands are 2 dB (typ.) higher than C-band specifications (3 dB with O-band configurations, 5 dB for 1647 – 1655 nm band); 8-12 dB higher for Visible region, 6-7 dB for 735nm-1.1μm, and 3-4 dB for 2 μm Input Wavelength Bands. Consult OEwaves Sales for other details.



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